

IN THE SPECIFICATION

32609 Please replace the paragraph at page 3, lines 16-26, with the following rewritten paragraph:

In the known loop-back testing method, however, the clock source of the transmitter TX is the same as that of the receiver RX. Since the same clock source is used, there is no frequency offset between the clocks. The PI cannot properly activate itself if there is no frequency offset. For example, the PI keeps locking itself to a certain point in [[its]] the clock phase position diagram. Accordingly, testing concerning this PI remains unsatisfactory, so the fault coverage of the CDR circuit does not rise.

Please replace the heading at page 7, line 15, with the following rewritten heading:

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE DRAWING DRAWINGS

Please replace the paragraph beginning at page 17, line 9 to page 18, line 3, with the following rewritten paragraph:

A loop-back path is an electrical path for looping output serial data from the transmitter back to the receiver. In this embodiment, serial data is looped back crosswise between adjacent channels. For example, serial data transmitted from a first channel A-ch is looped back to a second channel B-ch. On the other hand, serial data transmitted from the second channel B-ch is looped back to the first channel A-ch. This loop-back path need only be formed at least either outside or inside the semiconductor integrated circuit device chip. In this embodiment, the loop-back path is formed inside the semiconductor integrated circuit device chip. The advantage of the loop-back path formed inside the chip is that the semiconductor integrated circuit device can be tested without the device [[is]] being connected to a testing substrate having a loop-back path. Therefore, the receiver can be